

Title (en)
CHARGE-COUPLED IMAGE SENSOR ARRANGEMENT

Publication
EP 0193977 A3 19861001 (EN)

Application
EP 86200157 A 19860205

Priority
NL 8500337 A 19850207

Abstract (en)
[origin: EP0193977A2] @ The invention relates to a charge-coupled image sensor of the line transfer type comprising a number of parallel lines (2-6) which are each constituted by an n-phase CCD. An electrode (12-16) of each CCD is arranged parallel to this CCD separately for each CCD. The other (n-1) electrodes (17-20) extend transversely to the charge transport direction over all CCD's. The first-mentioned electrode (12-16) is used as a selection gate and is moreover used, depending upon the applied voltage, as an integration gate or as a blocking gate during the integration period.

IPC 1-7
H04N 3/15; **H01L 27/14**

IPC 8 full level
H01L 27/14 (2006.01); **H01L 27/148** (2006.01); **H04N 3/15** (2006.01); **H04N 5/32** (2006.01); **H04N 5/376** (2011.01)

CPC (source: EP US)
H01L 27/14831 (2013.01 - EP US); **H04N 25/745** (2023.01 - EP US)

Citation (search report)

- [YD] US 4242700 A 19801230 - WEIMER PAUL K [US]
- [Y] EP 0106286 A2 19840425 - TOSHIBA KK [JP]
- [A] US 4032903 A 19770628 - WEIMER PAUL KESSLER

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WO9115875A1

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AT DE FR GB IT NL

DOCDB simple family (publication)
EP 0193977 A2 19860910; **EP 0193977 A3 19861001**; **EP 0193977 B1 19910109**; AT E59922 T1 19910115; AU 5324686 A 19860814; AU 583885 B2 19890511; CA 1257684 A 19890718; DE 3676720 D1 19910214; ES 551617 A0 19870216; ES 8703684 A1 19870216; JP S61184062 A 19860816; NL 8500337 A 19860901; US 4799109 A 19890117

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